

Receipt date: 06/16/2008

PTO/SB/08A(10-01)
Approved for use through 10/31/2002, OMB 651-0031
US Patent & Trademark Office: U.S. DEPARTMENT OF COMMERCE
Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/081,818
Filing Date	February 20, 2002
First Named Inventor	Eldridge, Jerome
Group Art Unit	2818
Examiner Name	Ho, Tu-Tu

Sheet 1 of 8

Attorney Docket No: 1303.045US1

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-20010017369A1	08/30/2001	Iwasaki, Shingo , et al.	01/04/2001
	US-20010040430A1	11/15/2001	Ito, Hiroshi , et al.	08/07/1998
	US-20020002216A1	01/03/2002	Tooley, Patricia A.	04/11/2001
	US-20020004276A1	01/10/2002	Ahn, Kie Y., et al.	08/30/2001
	US-20020004277A1	01/10/2002	Ahn, Kie Y., et al.	08/30/2001
	US-20020051859A1	05/02/2002	Iida, Tetsuya , et al.	10/29/2001
	US-20020058578A1	05/16/2002	Shindo, Ayako	11/29/2000
	US-20020076070A1	06/20/2002	Yoshikawa, Takamasa , et al.	12/11/2001
	US-20020110973A1	08/15/2002	Liou, J. W., et al.	02/13/2001
	US-20020110983A1	08/15/2002	Liu, C. C., et al.	02/09/2001
	US-20020113261A1	05/02/2002	Iwasaki, Tomio , et al.	08/30/2001
	US-20020117963A1	08/29/2002	Chuman, Takashi , et al.	12/28/2001
	US-20020125490A1	09/12/2002	Chuman, Takashi , et al.	12/28/2001
	US-20020130338A1	09/19/2002	Ahn, Kie Y., et al.	03/15/2001
	US-20020155688A1	10/24/2002	Ahn, Kie Y.	04/20/2001
	US-20020172799A1	11/21/2002	Subramanian, Ramesh	05/16/2001
	US-20030026697A1	02/06/2003	Subramanian, Ramesh , et al.	08/02/2001
	US-20030048745A1	03/13/2003	Yoshikawa, Takamasa , et al.	01/05/2001
	US-20030067046A1	04/10/2003	Iwasaki, Tomio , et al.	11/18/2002
	US-20030130127A1	07/10/2003	Hentges, Patrick J., et al.	01/09/2002
	US-20030142569A1	07/31/2003	Forbes, Leonard	01/30/2002
	US-20030162399A1	08/28/2003	Singh, Rajiv K., et al.	10/01/2002
	US-20040038554A1	02/26/2004	Ahn, Kie Y.	08/21/2002
	US-20040043541A1	03/04/2004	Ahn, Kie Y., et al.	08/29/2002
	US-20040066484A1	04/08/2004	Tokailin, Hiroshi , et al.	06/13/2003
	US-20040110348A1	06/10/2004	Ahn, Kie Y., et al.	12/04/2002
	US-20040110391A1	06/10/2004	Ahn, K. Y., et al.	12/04/2002
	US-20040144980A1	07/29/2004	Ahn, Kie Y., et al.	01/29/2003
	US-20040164357A1	08/26/2004	Ahn, Kie Y., et al.	02/27/2004
	US-20040164365A1	08/26/2004	Ahn, Kie Y., et al.	02/27/2004
	US-20040169453A1	09/02/2004	Ahn, Kie Y., et al.	02/26/2004
	US-20040175882A1	09/09/2004	Ahn, Kie Y., et al.	03/04/2003
	US-20040178439A1	09/16/2004	Ahn, Kie Y., et al.	03/24/2004
	US-20040183108A1	09/23/2004	Ahn, Kie Y.	01/27/2004
	US-20040185654A1	09/23/2004	Ahn, Kie Y.	01/30/2004
	US-20040189175A1	09/30/2004	Ahn, Kie Y., et al.	03/29/2004
	US-20040214399A1	10/28/2004	Ahn, Kie Y., et al.	04/22/2003
	US-20040219783A1	11/04/2004	Ahn, Kie Y., et al.	05/25/2004
	US-20040222476A1	11/11/2004	Ahn, K. Y., et al.	06/09/2004
	US-20040248398A1	12/09/2004	Ahn, Kie Y., et al.	07/12/2004

EXAMINER

/Tu-Tu Ho/ (08/01/2008)

DATE CONSIDERED

08/01/2008

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. Applicant's unique citation designation (optional): Applicant is to place a check mark here if English language translation is attached

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /TH/ (08/01/2008)

Receipt date: 06/16/2008

PTO/SB/08A(10-01)

Approved for use through 10/31/2002. OMB 651-0031
US Patent & Trademark Office: U.S. DEPARTMENT OF COMMERCE
Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/081,818
Filing Date	February 20, 2002
First Named Inventor	Eldridge, Jerome
Group Art Unit	2818
Examiner Name	Ho, Tu-Tu

Sheet 2 of 8

Attorney Docket No: 1303.045US1

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-20040251815A1	12/16/2004	Tokailin, Hiroshi , et al.	06/13/2003
	US-20040251841A1	12/16/2004	Negishi, Nobuyasu , et al.	05/24/2004
	US-20040262700A1	12/30/2004	Ahn, Kie Y., et al.	06/24/2003
	US-20040266217A1	12/30/2004	Kim, K. , et al.	06/23/2004
	US-20050009370A1	01/13/2005	Ahn, Kie Y.	08/04/2004
	US-20050020017A1	01/27/2005	Ahn, Kie Y., et al.	06/24/2003
	US-20050023584A1	02/03/2005	Derderian, G. J., et al.	02/03/2005
	US-20050023594A1	02/03/2005	Ahn, K. Y., et al.	08/31/2004
	US-20050023624A1	02/03/2005	Ahn, K. Y., et al.	08/31/2004
	US-20050023625A1	02/03/2005	Ahn, K. Y., et al.	08/31/2004
	US-20050023627A1	02/03/2005	Ahn, K. Y., et al.	08/31/2004
	US-20050026374A1	02/03/2005	Ahn, K. Y., et al.	08/31/2004
	US-20050029547A1	02/10/2005	Ahn, K. Y., et al.	08/31/2004
	US-20050029604A1	02/21/2005	Ahn, K. Y., et al.	08/31/2004
	US-20050029605A1	02/10/2005	Ahn, K Y., et al.	08/31/2004
	US-20050030825A1	02/10/2005	Ahn, K. Y.	08/31/2004
	US-20050032292A1	02/10/2005	Ahn, K. Y., et al.	08/31/2004
	US-20050034662A1	02/17/2005	Ahn, K. Y.	08/31/2004
	US-20050037563A1	02/17/2005	Ahn, Kie Y.	08/31/2004
	US-20050054165A1	03/10/2005	Ahn, K. Y., et al.	03/31/2003
	US-20050077519A1	04/14/2005	Ahn, Kie , et al.	10/10/2003
	US-20050124109A1	06/09/2005	Quevado-Lopez, Manuel A., et al.	12/03/2003
	US-20050124174A1	06/09/2005	Ahn, K. Y., et al.	01/07/2005
	US-20050124175A1	06/09/2005	Ahn, Kie , et al.	01/13/2005
	US-20050138262A1	06/23/2005	Forbes, Leonard	12/18/2003
	US-20050145957A1	07/07/2005	Ahn, K. Y., et al.	02/16/2005
	US-20050158973A1	07/21/2005	Ahn, K. Y., et al.	01/14/2005
	US-20050164521A1	07/28/2005	Ahn, Kie Y., et al.	03/21/2005
	US-20050227442A1	10/13/2005	Ahn, K. Y., et al.	06/09/2005
	US-20050277256A1	12/15/2005	Ahn, K. Y., et al.	07/11/2005
	US-20050280067A1	12/22/2005	Ahn, K. Y., et al.	08/26/2005
	US-20060000412A1	01/05/2006	Ahn, K. Y., et al.	08/29/2005
	US-20060001151A1	01/05/2006	Ahn, K. Y., et al.	08/26/2005
	US-20060003517A1	01/05/2006	Ahn, K. Y., et al.	08/29/2005
	US-20060024975A1	02/02/2006	Ahn, Kie Y., et al.	08/02/2004
	US-20060035405A1	02/16/2006	Park, H. , et al.	07/28/2005
	US-20060043492A1	03/02/2006	Ahn, K. Y., et al.	08/29/2005
	US-20060043504A1	03/02/2006	Ahn, K. Y., et al.	08/31/2004
	US-20060046505A1	03/02/2006	Ahn, K. Y., et al.	08/26/2004
	US-20060046522A1	03/02/2006	Ahn, K. Y., et al.	08/31/2004

EXAMINER

/Tu-Tu Ho/ (08/01/2008)

DATE CONSIDERED

08/01/2008

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language translation is attached

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /TH/ (08/01/2008)

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/081,818
Filing Date	February 20, 2002
First Named Inventor	Eldridge, Jerome
Group Art Unit	2818
Examiner Name	Ho, Tu-Tu

Sheet 3 of 8

Attorney Docket No: 1303.045US1

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-20060054943A1	03/16/2006	Li, Hong-Jyh , et al.	09/14/2004
	US-20060128168A1	06/15/2006	Ahn, K. Y., et al.	12/13/2004
	US-20060148180A1	07/06/2006	Ahn, K. Y., et al.	01/05/2005
	US-20060176645A1	08/10/2006	Ahn, K. Y., et al.	02/08/2005
	US-20060183272A1	08/17/2006	Ahn, K. Y., et al.	02/15/2005
	US-20060189154A1	08/24/2006	Ahn, K. Y., et al.	02/23/2005
	US-20060223337A1	10/05/2006	Ahn, K. Y., et al.	03/29/2005
	US-20060244082A1	11/02/2006	Ahn, K. Y., et al.	04/28/2005
	US-20060281330A1	12/14/2006	Ahn, K. Y., et al.	06/14/2005
	US-20070020835A1	01/25/2007	Ahn, K. Y., et al.	09/28/2006
	US-20070048926A1	03/01/2007	Ahn, K Y.	08/31/2005
	US-20070048953A1	03/01/2007	Gealy, Dan , et al.	08/30/2005
	US-20070048989A1	03/01/2007	Ahn, Kie Y., et al.	08/30/2005
	US-20070049023A1	03/01/2007	Ahn, Kie Y., et al.	08/29/2005
	US-20070049054A1	03/01/2007	Ahn, Kie Y., et al.	08/31/2005
	US-20070134931A1	06/14/2007	Ahn, K. Y., et al.	12/08/2005
	US-20070158765A1	07/12/2007	Ahn, K. Y., et al.	01/10/2006
	US-20080014689A1	01/17/2008	Cleavelin, C. R., et al.	07/07/2006
	US-20080032424A1	02/07/2008	Ahn, K. Y., et al.	08/03/2006
	US-20080042211A1	02/21/2008	Bhattacharyya, A. , et al.	08/18/2006
	US-20080057659A1	03/06/2008	Forbes, Leonard	08/31/2006
	US-20080057690A1	03/06/2008	Forbes, Leonard	08/31/2006
	US-20080087945A1	04/17/2008	Forbes, L. , et al.	08/31/2006
	US-3,738,817	06/12/1973	Benjamin, J. S.	03/01/1971
	US-3,833,386	09/03/1974	Wood, Louis L., et al.	07/07/1972
	US-3,903,232	09/02/1975	Wood, Louis L., et al.	02/19/1974
	US-3,926,568	12/16/1975	Benjamin, John S., et al.	08/28/1974
	US-3,959,191	05/25/1976	Kehr, Clifton L., et al.	12/30/1974
	US-4,017,322	04/12/1977	Kawai, Motochika , et al.	06/09/1975
	US-4,137,200	01/30/1979	Wood, Louis L., et al.	06/10/1977
	US-4,293,679	10/06/1981	Cogliano, Joseph A.	05/27/1980
	US-4,302,620	11/24/1981	Chu, Chin-Chiun	10/29/1980
	US-4,358,397	11/09/1982	Chu, Chin C.	12/31/1980
	US-4,403,083	09/06/1983	Marans, Nelson S., et al.	08/31/1982
	US-4,940,636	07/10/1990	Brock, Lieselotte , et al.	07/21/1988
	US-4,961,004	10/02/1990	Bryan, Philip S., et al.	11/16/1989
	US-4,963,753	10/16/1990	Bryan, Philip S., et al.	10/16/1989
	US-4,963,754	10/16/1990	Bryan, Philip S., et al.	11/16/1989
	US-4,967,085	10/30/1990	Bryan, Philip S., et al.	11/16/1989
	US-4,967,087	10/30/1990	Bryan, Philip S., et al.	11/16/1989

EXAMINER

/Tu-Tu Ho/ (08/01/2008)

DATE CONSIDERED

08/01/2008

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /TH/ (08/01/2008)

Substitute for form 1449A/PTO

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number 10/081,818**Filing Date** February 20, 2002**First Named Inventor** Eldridge, Jerome**Group Art Unit** 2818**Examiner Name** Ho, Tu-Tu

Sheet 4 of 8

Attorney Docket No: 1303.045US1

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-4,972,086	11/20/1990	Bryan, Philip S., et al.	11/16/1989
	US-4,972,516	11/20/1990	Bryan, Philip S., et al.	11/16/1989
	US-4,975,014	12/04/1990	Rufin, Antonio C., et al.	09/01/1989
	US-4,975,588	12/04/1990	Bryan, Philip S., et al.	11/16/1989
	US-4,980,559	12/25/1990	Bryan, Philip S., et al.	11/15/1989
	US-4,980,560	12/25/1990	Bryan, Philip S., et al.	11/16/1989
	US-4,983,847	01/08/1991	Bryan, Philip S., et al.	01/16/1989
	US-4,988,880	01/29/1991	Bryan, Philip S., et al.	02/03/1989
	US-4,990,282	02/05/1991	Bryan, Philip S., et al.	06/27/1990
	US-4,992,205	02/12/1991	Bryan, Philip S., et al.	06/27/1990
	US-4,994,205	02/19/1991	Bryan, Philip S., et al.	06/29/1990
	US-4,996,003	02/26/1991	Bryan, Philip S., et al.	06/29/1990
	US-5,008,034	04/16/1991	Bryan, Philip S., et al.	06/29/1990
	US-5,017,791	05/21/1991	Bryan, Philip S., et al.	11/16/1989
	US-5,075,536	12/24/1991	Towe, Carey A., et al.	05/17/1990
	US-5,084,606	01/28/1992	Bailey, John M., et al.	05/17/1990
	US-5,095,218	03/10/1992	Bryan, Philip S., et al.	07/20/1990
	US-5,619,450	04/08/1997	Takeguchi, T.	05/15/1995
	US-5,962,959	10/05/1999	Iwasaki, Shingo, et al.	03/03/1998
	US-5,990,605	11/23/1999	Yoshikawa, Takamasa, et al.	03/20/1998
	US-5,998,528	12/07/1999	Tsipursky, Semeon, et al.	02/02/1998
	US-6,023,124	02/08/2000	Chuman, Takashi, et al.	02/27/1998
	US-6,023,125	02/08/2000	Yoshikawa, T., et al.	03/09/1998
	US-6,066,922	05/23/2000	Iwasaki, Shingo	08/07/1998
	US-6,087,695	07/11/2000	Chen, C.	08/20/1999
	US-6,103,419	08/15/2000	Saidi, M. Y., et al.	09/06/1996
	US-6,125,062	09/26/2000	Ahn, Kie, et al.	08/26/1998
	US-6,130,503	10/10/2000	Negishi, Nobuyasu, et al.	02/27/1998
	US-6,137,025	10/24/2000	Ebbinghaus, Bartley B., et al.	06/22/1999
	US-6,141,260	10/31/2000	Ahn, Kie, et al.	08/27/1998
	US-6,144,155	11/07/2000	Yoshikawa, Takamasa, et al.	05/14/1998
	US-6,147,443	11/14/2000	Yoshikawa, Takamasa, et al.	05/14/1998
	US-6,166,487	12/26/2000	Negishi, Nobuyasu, et al.	03/07/2000
	US-6,184,612	02/06/2001	Negishi, Nobuyasu, et al.	08/07/1998
	US-6,259,198	07/10/2001	Yanagisawa, Shuuchi, et al.	12/23/1998
	US-6,274,937	08/14/2001	Ahn, Kie Y., et al.	02/01/1999
	US-6,278,230	08/21/2001	Yoshizawa, Atsushi, et al.	08/07/1998
	US-6,281,042	08/28/2001	Ahn, K. Y., et al.	08/31/1998
	US-6,285,123	09/04/2001	Yamada, Takashi, et al.	09/10/1999
	US-6,297,103	10/02/2001	Ahn, Kie, et al.	02/28/2000

/Tu-Tu Ho/ (08/01/2008)

EXAMINER

DATE CONSIDERED

08/01/2008

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /TH/ (08/01/2008)

Receipt date: 06/16/2008

PTO/SB/08A(10-01)
Approved for use through 10/31/2002. OMB 051-0031
US Patent & Trademark Office: U.S. DEPARTMENT OF COMMERCE

Substitute for form 1449A/PTO

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/081,818
Filing Date	February 20, 2002
First Named Inventor	Eldridge, Jerome
Group Art Unit	2818
Examiner Name	Ho, Tu-Tu

Sheet 5 of 8

Attorney Docket No: 1303.045US1

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-6,313,518	11/06/2001	Ahn, K. , et al.	03/02/2000
	US-6,316,873	11/13/2001	Ito, Hiroshi , et al.	08/07/1998
	US-6,320,091	11/20/2001	Ebbinghaus, Bartley B., et al.	06/22/1999
	US-6,350,704	02/26/2002	Ahn, K. , et al.	10/14/1997
	US-6,388,376	05/14/2002	Negishi, Nobuyasu , et al.	08/05/1999
	US-6,400,070	06/04/2002	Yamada, Takashi , et al.	08/07/1998
	US-6,404,124	06/11/2002	Sakemura, Kazuto , et al.	07/28/1999
	US-6,404,681	06/11/2002	Hirano, Y.	10/31/2000
	US-6,429,237	08/06/2002	Tooley, Patricia A.	04/11/2001
	US-6,454,912	09/24/2002	Ahn, Kie Y., et al.	03/15/2001
	US-6,472,803	10/29/2002	Yoshizawa, Atsushi , et al.	08/06/1999
	US-6,489,648	12/03/2002	Iwasaki, Tomio , et al.	08/30/2001
	US-6,492,288	12/10/2002	Shindo, Ayako	11/29/2000
	US-6,495,436	12/17/2002	Ahn, Kie Y., et al.	02/09/2001
	US-6,514,820	02/04/2003	Ahn, Kie Y., et al.	08/29/2001
	US-6,514,828	02/04/2003	Ahn, Kie Y., et al.	04/20/2001
	US-6,534,420	03/18/2003	Ahn, Kie Y., et al.	07/18/2001
	US-6,544,846	04/08/2003	Ahn, Kie Y., et al.	04/15/2002
	US-6,552,383	04/22/2003	Ahn, Kie Y., et al.	05/11/2001
	US-6,570,248	05/27/2003	Ahn, Kie Y., et al.	08/08/2001
	US-6,580,124	06/17/2003	Cleeves, James M., et al.	08/14/2000
	US-6,586,792	07/01/2003	Ahn, Kie Y., et al.	03/15/2001
	US-6,602,053	08/05/2003	Subramaniam, Ramesh , et al.	08/02/2001
	US-6,608,378	08/19/2003	Ahn, Kie Y., et al.	08/26/2002
	US-6,641,887	11/04/2003	Lida, Tetsuya , et al.	10/29/2001
	US-6,661,058	12/09/2003	Ahn, Kie Y., et al.	02/11/2002
	US-6,700,132	03/02/2004	Chuman, Takashi , et al.	12/28/2001
	US-6,710,465	03/23/2004	Song, S. , et al.	01/16/2003
	US-6,710,538	03/23/2004	Ahn, Kie Y., et al.	08/26/1998
	US-6,720,216	04/13/2004	Forbes, Leonard	08/29/2002
	US-6,720,221	04/13/2004	Ahn, Kie , et al.	08/30/2001
	US-6,744,063	06/01/2004	Yoshikawa, Takamasa , et al.	01/05/2001
	US-6,756,298	06/29/2004	Ahn, Kie Y., et al.	08/01/2002
	US-6,759,151	07/06/2004	Lee, Kang N.	05/22/2002
	US-6,767,795	07/27/2004	Ahn, Kie Y., et al.	01/17/2002
	US-6,774,050	08/10/2004	Ahn, Kie , et al.	01/31/2003
	US-6,787,413	09/07/2004	Ahn, Kie Y.	06/17/2002
	US-6,787,992	09/07/2004	Chuman, Takashi , et al.	12/28/2001
	US-6,790,791	09/14/2004	Ahn, Kie Y., et al.	08/15/2002
	US-6,794,709	08/21/2004	Ahn, Kie Y., et al.	08/30/2001

EXAMINER

/Tu-Tu Ho/ (08/01/2008)

DATE CONSIDERED

08/01/2008

Substitute Disclosure Statement Form (PTO-1449)
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /TH/ (08/01/2008)

Receipt date: 06/16/2008

PTO/SB/08A(10-01)
Approved for use through 10/31/2002. OMB 051-0031
US Patent & Trademark Office: U.S. DEPARTMENT OF COMMERCE

Substitute for form 1449A/PTO

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number 10/081,818

Filing Date February 20, 2002

First Named Inventor Eldridge, Jerome

Group Art Unit 2818

Examiner Name Ho, Tu-Tu

Sheet 6 of 8

Attorney Docket No: 1303.045US1

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-6,803,326	10/12/2004	Ahn, Kie Y., et al.	07/20/2001
	US-6,812,100	11/02/2004	Ahn, K. Y., et al.	03/13/2002
	US-6,828,045	12/07/2004	Tokailin, Hiroshi , et al.	06/13/2003
	US-6,833,285	12/21/2004	Ahn, Kie Y., et al.	09/12/2000
	US-6,833,308	12/21/2004	Ahn, K. Y., et al.	08/30/2001
	US-6,835,111	12/28/2004	Ahn, Kie Y., et al.	11/26/2001
	US-6,838,404	01/04/2005	Hentges, Patrick J., et al.	01/09/2002
	US-6,844,203	01/18/2005	Ahn, Kie Y., et al.	08/30/2001
	US-6,846,574	01/25/2005	Subramanian, Ramesh	05/16/2001
	US-6,852,167	02/08/2005	Ahn, K. Y.	03/01/2001
	US-6,858,120	02/22/2005	Ahn, Kie , et al.	08/09/2002
	US-6,858,444	02/22/2005	Ahn, K. Y., et al.	06/20/2003
	US-6,858,865	02/22/2005	Ahn, Kie , et al.	02/23/2001
	US-6,884,739	04/26/2005	Ahn, K. Y., et al.	08/15/2002
	US-6,893,984	05/17/2005	Ahn, Kie Y., et al.	02/20/2002
	US-6,900,122	05/31/2005	Ahn, Kie Y., et al.	12/20/2001
	US-6,914,800	07/05/2005	Ahn, K. Y., et al.	08/31/2004
	US-6,919,266	07/19/2005	Ahn, Kie Y., et al.	07/24/2001
	US-6,921,702	07/26/2005	Ahn, Kie Y., et al.	07/30/2002
	US-6,930,346	08/16/2005	Ahn, K. Y., et al.	08/31/2004
	US-6,953,730	10/11/2005	Ahn, K. Y., et al.	12/20/2001
	US-6,958,302	10/25/2005	Ahn, K. Y., et al.	12/04/2002
	US-6,960,538	11/01/2005	Ahn, Kie Y., et al.	08/21/2002
	US-6,970,053	11/29/2005	Akram, S. , et al.	05/22/2003
	US-6,979,855	12/27/2005	Ahn, K. Y., et al.	01/27/2004
	US-6,989,573	01/24/2006	Ahn, Kie Y., et al.	10/10/2003
	US-7,026,694	04/11/2006	Ahn, K. Y., et al.	08/31/2004
	US-7,045,430	05/16/2006	Ahn, K. Y., et al.	05/02/2002
	US-7,049,192	05/23/2006	Ahn, K. Y., et al.	06/24/2003
	US-7,064,058	06/20/2006	Ahn, K. Y., et al.	01/30/2004
	US-7,081,421	07/25/2006	Ahn, K. Y., et al.	08/26/2004
	US-7,084,078	08/01/2006	Ahn, K. Y., et al.	08/29/2002
	US-7,101,813	09/05/2006	Ahn, k. y., et al.	12/04/2002
	US-7,133,316	11/07/2006	Lue, Hang-Ting	06/02/2004
	US-7,235,501	06/26/2007	Ahn, K. Y., et al.	12/13/2004
	US-7,365,027	04/29/2008	Ahn, A. Y., et al.	03/29/2005
	US-7,372,096	05/13/2008	Forbes, L. , et al.	06/20/2006
	US-7,372,097	05/13/2008	Forbes, L. , et al.	06/20/2006
	US-7,391,072	06/24/2008	Forbes, L. , et al.	06/20/2006

/Tu-Tu Ho/ (08/01/2008)

08/01/2008

EXAMINER

DATE CONSIDERED

Substitute Disclosure Statement Form (PTO-1449)
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /TH/ (08/01/2008)

Substitute for form 1449A/PTO

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/081,818
Filing Date	February 20, 2002
First Named Inventor	Eldridge, Jerome
Group Art Unit	2818
Examiner Name	Ho, Tu-Tu

Sheet 7 of 8

Attorney Docket No: 1303.045US1

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	T ²
-----------------------	---------------------	------------------	--	----------------

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		AARIK, JAAN , "Atomic layer growth of epitaxial TiO ₂ thin films from TiCl ₄ and H ₂ O on alpha -Al ₂ O ₃ substrates", <u>Journal of Crystal Growth</u> , 242(1-2), (2002),189-198	
		AARIK, JAAN , "Influence of substrate temperature on atomic layer growth and properties of HfO ₂ thin films", <u>Thin Solid Films</u> , 340(1-2), (1999),110-116	
		AARIK, JAAN , "Phase transformations in hafnium dioxide thin films grown by atomic layer deposition at high temperatures", <u>Applied Surface Science</u> , 173(1-2), (March 2001),15-21	
		CHEN, F. , "A study of mixtures of HfO ₂ and TiO ₂ as high-k gate dielectrics", <u>Microelectronic Engineering</u> 72, (2004),263	
		CHEN, F. , et al., "Hafnium Titanate as a High-K Gate Insulator", <u>Electrochemical Society Proceedings</u> , Vol. 2004-01, (2004),278-285	
		CONLEY, J. F., "Atomic Layer Deposition of Hafnium Oxide Using Anhydrous Hafnium Nitrate", <u>Electrochemical and Solid-State Letters</u> , 5(5), (May 2002),C57-C59	
		DOMAGALA, R. F., et al., "The Pseudobinary Ti-ZrO ₂ ", <u>J. Am. Ceramic Soc.</u> , Vol. 56, Paper first presented in 1970,(1973),584-587	
		FORBES, "HAFNIUM TANTALUM OXYNITRIDE HIGH-K DIELECTRIC AND METAL GATES", <u>U.S. Appln. Serial No. 11/515,114</u> , filed <u>August 31, 2005</u> , Attny docket no. 1303.185US1, client ref no 06-0073,	
		KIM, BYOUNG-YOUP , et al., "Comparison study for TiN films deposited from different method: chemical vapor deposition and atomic layer deposition", <u>Mechanisms of Surface and Microstructure Evolution in Deposited Films and Film Structures Symposium (Materials Research Society Symposium Proceedings Vol.672)</u> , (2001),7.8.1-7.8.6	
		KUKLI, KAUPÖ , "Comparison of hafnium oxide films grown by atomic layer deposition from iodide and chloride precursors", <u>Thin Solid Films</u> , 416, (2002),72-79	
		LESKELA, M , "ALD precursor chemistry: Evolution and future challenges", <u>Journal de Physique IV (Proceedings)</u> , 9(8), (September 1999),837-852	
		NALWA, H. S., "Handbook of Thin Film Materials", <u>Deposition and Processing of thin Films</u> , Vol. 1, San Diego : Academic Press,(2002),114-119	
		ROBERTSON, JOHN , "Band offsets of wide-band-gap oxides and implications for future electronic devices", <u>Journal of Vacuum Science & Technology B: Microelectronics and Nanometer Structures</u> , 18(3), (May 2000),1785-1791	
		RUH, ROBERT , et al., "Phase Relations and Thermal Expansion in the System HfO ₂ -TiO ₂ ", <u>J. Am. Ceramic Soc.</u> , 59, (Nov.-Dec. 1976),495-499	

/Tu-Tu Ho/ (08/01/2008)

EXAMINER

DATE CONSIDERED

08/01/2008

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /TH/ (08/01/2008)

Receipt date: 06/16/2008

PTO/SB/08A(10-01)

Approved for use through 10/31/2002, OMB 651-0031
US Patent & Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/081,818
Filing Date	February 20, 2002
First Named Inventor	Eldridge, Jerome
Group Art Unit	2818
Examiner Name	Ho, Tu-Tu

Sheet 8 of 8

Attorney Docket No: 1303.045US1

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		SNEH, OFER , "Thin film atomic layer deposition equipment for semiconductor processing", Thin Solid Films, 402(1-2), (2002),248-261	
		SUNTOLA, T. , "Atomic Layer Epitaxy", Handbook of Crystal Growth, 3; Thin Films of Epitaxy, Part B: Growth Mechanics and Dynamics, Amsterdam,(1994),601-663	
		WILK, G. D., "High-K gate dielectrics: Current status and materials properties considerations", Journal of Applied Physics, 89(10), (May 2001),5243-5275	

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /TH/ (08/01/2008)

EXAMINER

/Tu-Tu Ho/ (08/01/2008)

DATE CONSIDERED

08/01/2008

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached